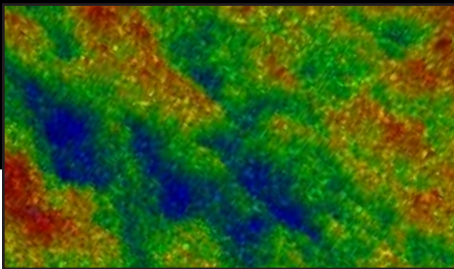
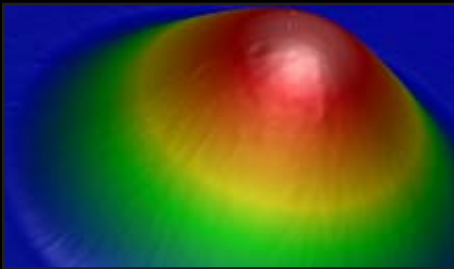
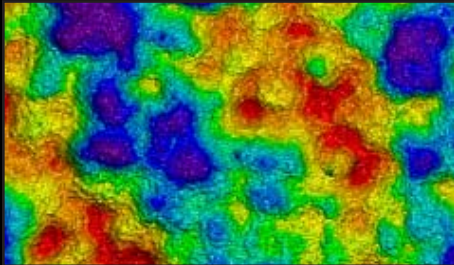


# zygo® NewView™ 600

## ZYGO CORPORATION'S NewView™ 600p 3D Optical Profiler

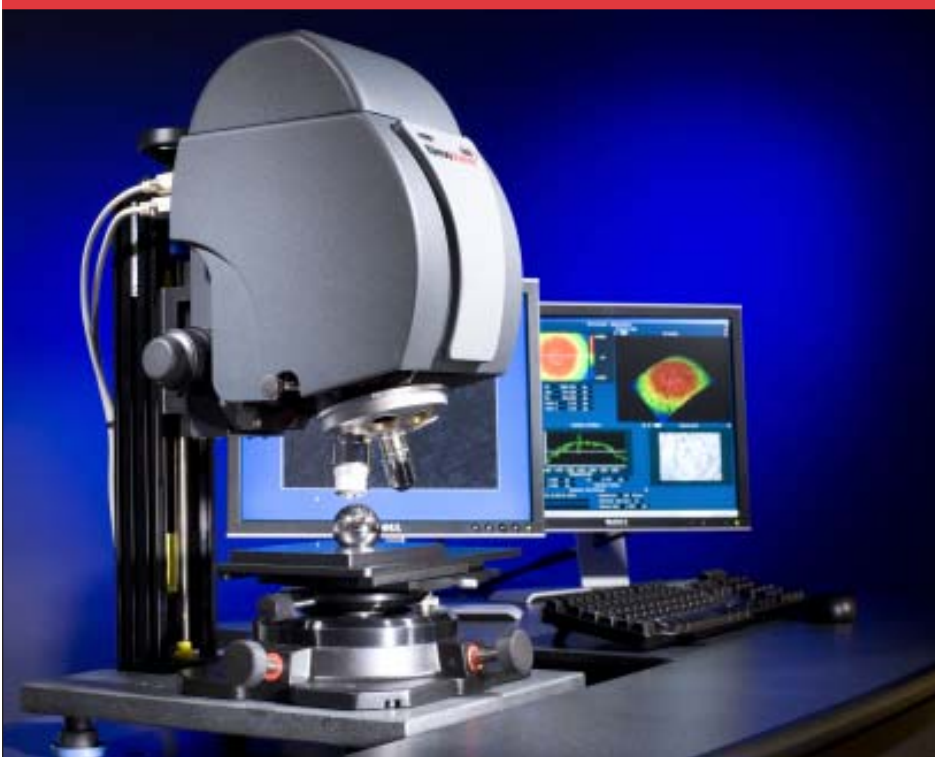


## Precise, Cost-Effective Optical Profiling for Smooth Surfaces

- **Fast 3D areal measurement**
- **High resolution and precision**
- **Simple operation**
- **Cost-effective, compact platform**
- **High quality imaging and reliability**
- **Comprehensive data analysis tools**

The NewView™ 600p provides precise, low-cost 3D profiling and quantitative surface topography measurements for both research and production applications. Based on *phase-shifting interferometry*, the NewView 600p provides fast, noncontact, high-resolution surface metrology on various smooth surfaces and materials, including glass, micro-optics, silicon wafers, optical and magnetic storage disks, ceramics, and more.

The NewView 600p offers superior value, simplified operation and flexibility – in a compact footprint. A full range of software features and analysis tools enable comprehensive 2D and 3D surface characterization. In addition, the NewView 600p continues to deliver the level of precision and quality that has become the trademark of ZYGO's NewView family of products. Simply put, the NewView 600p delivers optimal value, in combination with proven precision and quality.



## NewView™ 600p Specifications

### SYSTEM

- **Technology** Phase-shifting interferometry
- **Objectives** 2X, 2.5X, 5X, 10X, 20X, 50X, and 100X; long working distance objectives available
- **Field-of-View** Selectable from 0.05 to 3.5 millimeters; objective dependent
- **Illuminator** Computer controlled, long-life white light LED
- **Measurement Array** 640x480, user selectable
- **Vertical Resolution** < 0.1 nm (0.004  $\mu\text{m}$ )
- **Lateral Resolution** 0.34 to 5.00  $\mu\text{m}$  (14.2 to 204  $\mu\text{m}$ ); objective dependent
- **Maximum Data Points** 307,200 RMS
- **Repeatability** < 0.01 nm (0.0004  $\mu\text{m}$ )  $\text{RMS}\sigma$
- **Step Height Accuracy** = 0.75%
- **Step Height Repeatability** = 0.1% @1 $\sigma$
- **Max. Step Height** ~138 nm

**PRECISION** – Using ZYGO's phase-shifting interferometry technology the NewView 600p easily and quickly measures smooth, flat surfaces, with <0.1 nm vertical resolution, independent of magnification or field-of-view.

**FLEXIBILITY** – A key component of the NewView 600p is its configurability. Based on a modular architecture, the system can be easily configured to meet your needs. Standard accessories include a complete line of high quality interferometric objectives, manual and motorized turrets, and sample positioning stages. Also, a convenient breadboard is available to accept custom sample holders and positioning devices. Whether you need a versatile system with all the options, or a dedicated production setup, the NewView 600p can be easily optimized to meet your needs.

**SIMPLICITY** – Many instruments claim to be easy to use but often fall short. Not the NewView 600p! All measurements are fast, nondestructive and require no sample preparation. Areal surface data is rapidly acquired and processed, yielding more than 300,000 data points in seconds, or less. Objectives are easily interchanged using quick-mount adapters or selected using a multi-position turret - providing you with the magnification, field-of-view, and resolution you need, when you need it. Ergonomically positioned coarse, medium, and fine focus knobs, Real-Time Display, and automatic light level adjustment expedite sample setup.

**CHARACTERIZATION** – And of course, the system is powered by ZYGO's comprehensive metrology software package, MetroPro, providing complete 3D and 2D surface characterization, visualization, and processing options. In addition to advanced analysis, user-friendly MetroPro includes instrument control, password protection, statistical databases, programmable scripting, customizable layout, pass/fail flags, and much more.

*Not exactly sure what features you need today, or what you'll need tomorrow? The NewView 600p offers a full range of options and upgrades to meet your metrology and budgetary requirements, protecting your investment for years. From cost-effective bench-top research tools, to dedicated production systems, the NewView 600p optical profiler offers a complete metrology solution for today's leading-edge research and production applications.*

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